

Nyquist-Rate A/D Converters

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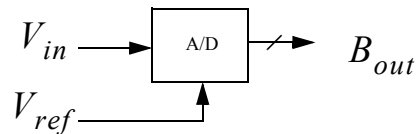


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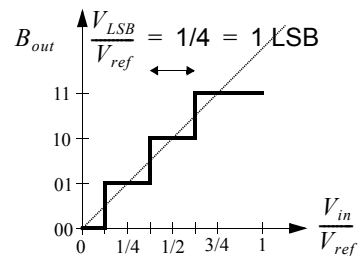
A/D Converter Basics



$$V_{ref}(b_1 2^{-1} + b_2 2^{-2} + \dots + b_N 2^{-N}) = V_{in} \pm x$$

$$\text{where } \left(-\frac{1}{2} V_{LSB} < x < \frac{1}{2} V_{LSB}\right) \quad (1)$$

- **Range of valid input values** produce the **same output signal** — **quantization error**.



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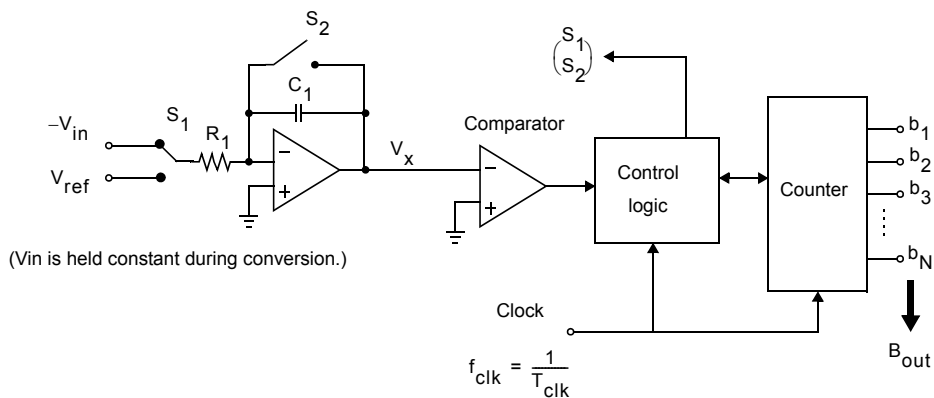
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Analog to Digital Converters

Low-to-Medium Speed, High Accuracy	Medium Speed, Medium Accuracy	High Speed, Low-to-Medium Accuracy
Integrating	Successive approximation	Flash
Oversampling (not Nyquist-rate)	Algorithmic	Two-step
		Interpolating
		Folding
		Pipelined
		Time-interleaved



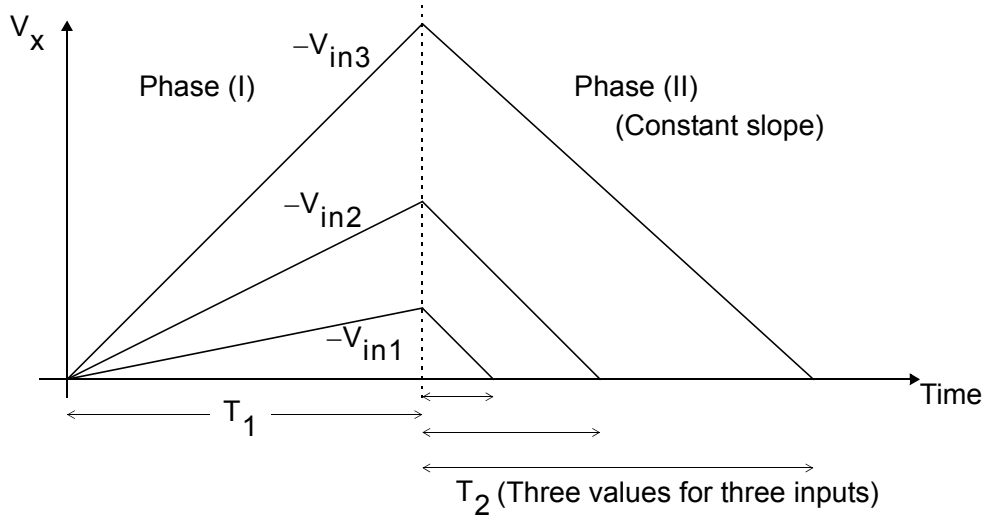
Integrating Converters



- Low offset and gain errors for low-speed applications
- Small amount of circuitry
- Conversion speed is 2^{N+1} times $1/T_{\text{clk}}$



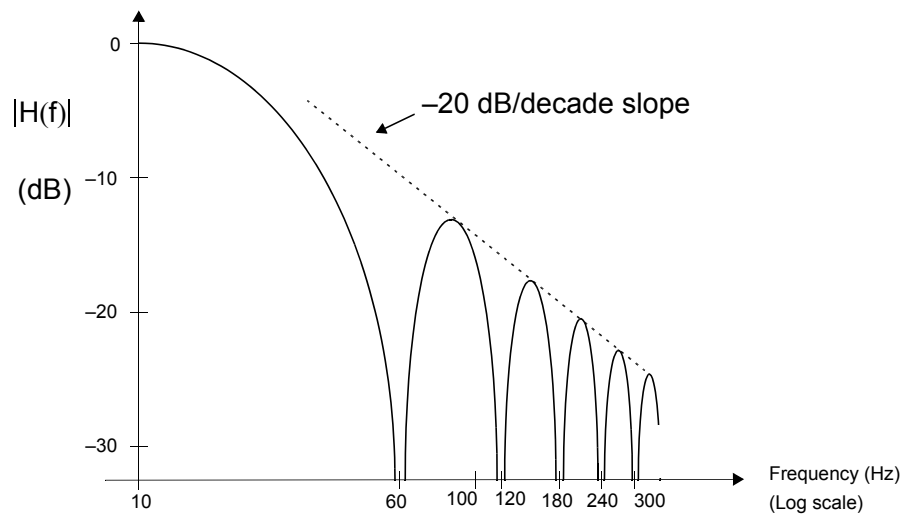
Integrating Converters



- Count at end of T_2 is digital output
- Does not depend on RC time-constant



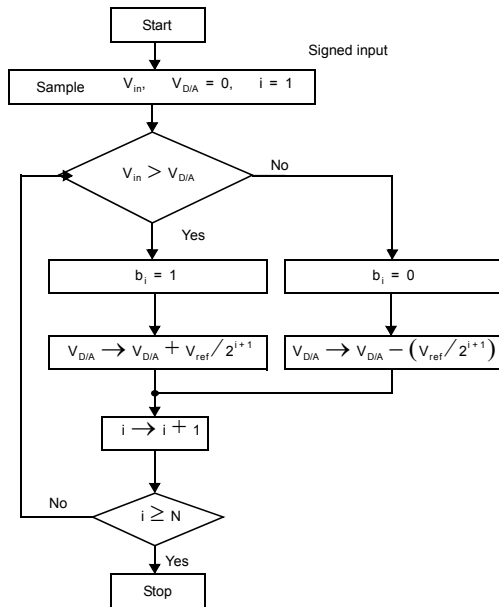
Integrating Converters



- Notches the input frequencies which are multiples of $1/T_1$



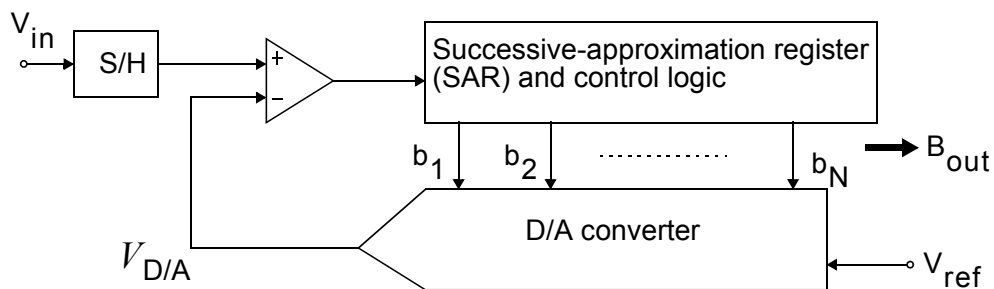
Successive-Approximation Converters



- Makes use of binary search algorithm
- Requires N steps for N-bit converter
- Successively “tunes” a signal until within 1 LSB of input
- Medium speed
- Moderate accuracy



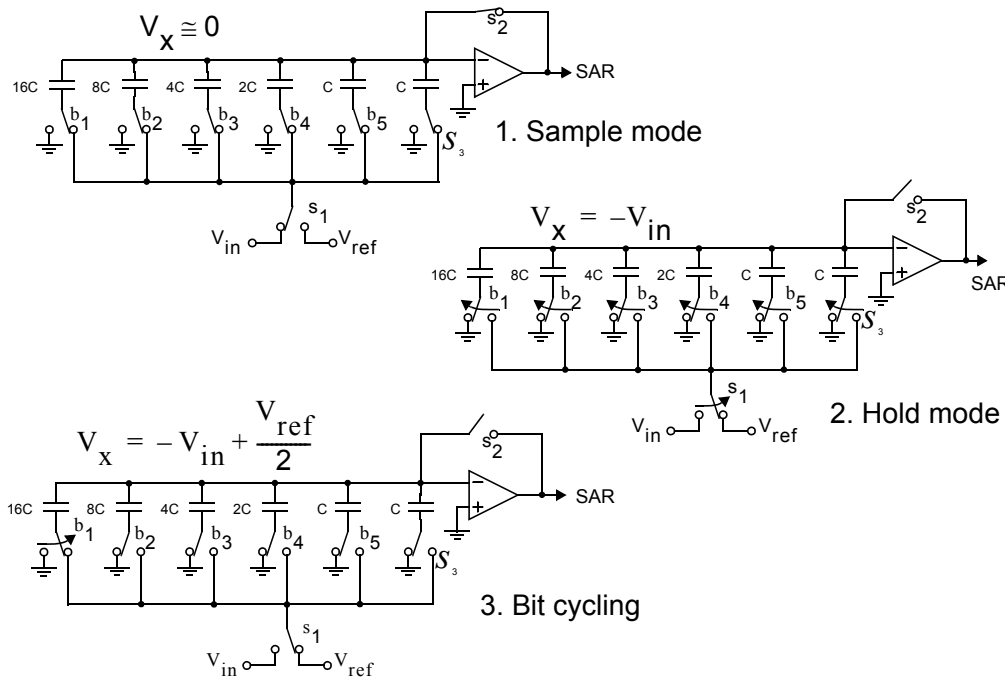
DAC Based Successive-Approximation



- Adjust $V_{D/A}$ until within 1 LSB of V_{in}
- Start with MSB and continue until LSB found
- D/A mainly determines overall accuracy
- Input S/H required



Charge Redistribution A/D

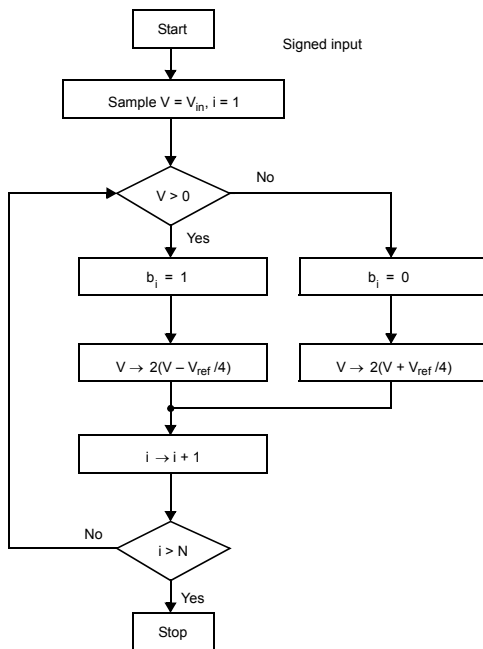


Charge Redistribution A/D

- McCreary, 75
- Combines S/H, D/A converter, and difference circuit
- *Sample mode*: Caps charged to V_{in} , compar reset.
- *Hold mode*: Caps switched to gnd so $V_x = -V_{in}$
- *Bit cycling*: Cap switched to V_{ref} . If $V_x < 0$ cap left connected to V_{ref} and bit=1. Otherwise, cap back to gnd and bit=0. Repeat N times
- Cap *bottom plates* connected to V_{ref} side to minimize parasitic capacitance at V_x . Parasitic cap does not cause conversion errors but it attenuates V_x .



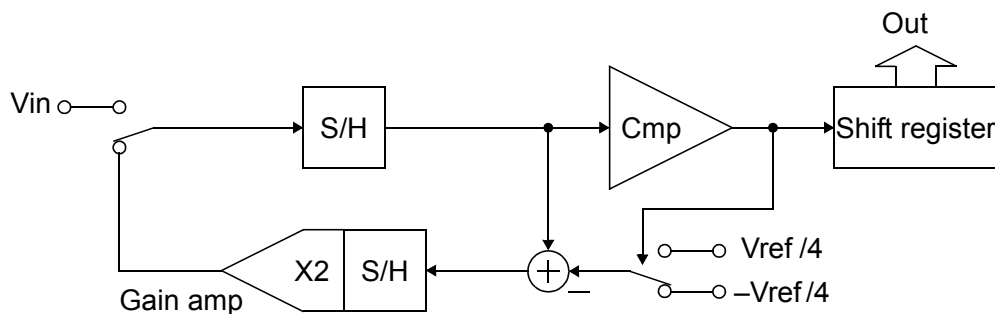
Algorithmic (or Cyclic) A/D Converter



- Operates similar to successive-approx converter
- Successive-approx halves ref voltage each cycle
- Algorithmic doubles error each cycle (leaving ref voltage unchanged)



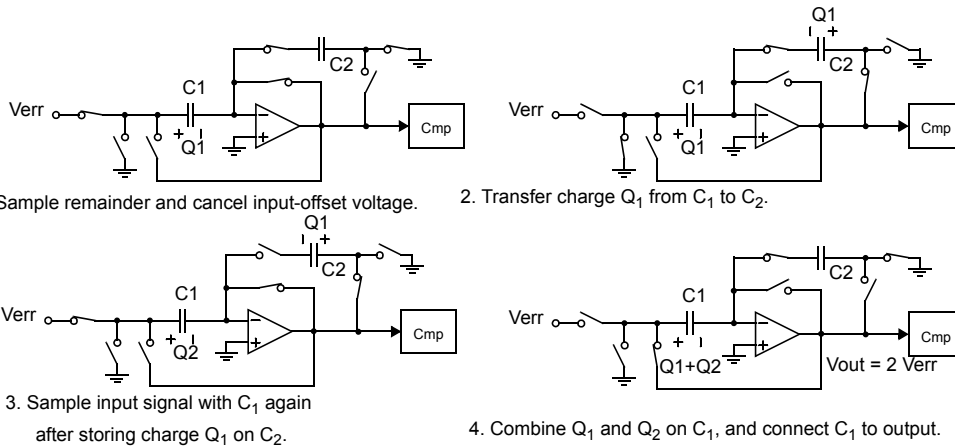
Ratio-Independent Algorithmic Converter



- McCharles, 77; Li, 84
- Small amount of circuitry — reuse cyclically in time
- Requires a high-precision multiply by 2 gain stage



Ratio-Independent Algorithmic Converter

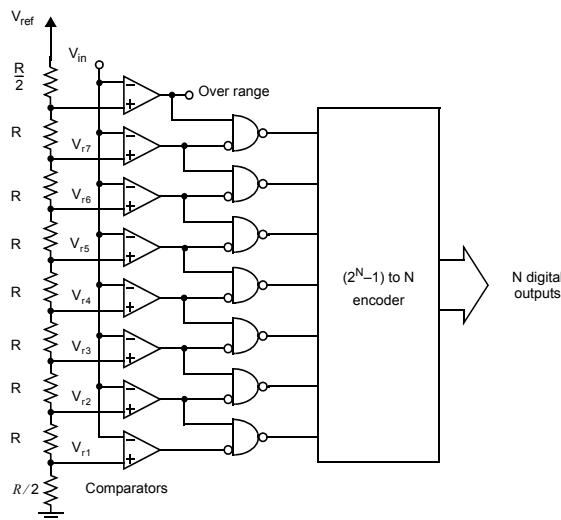


- Does not rely on cap matching
- Sample input twice using C_1 ; hold first charge in C_2 and re-combine with first charge on C_1



Flash (or Parallel) Converters

- Peetz, 86; Yoshii, 87; Hotta, 87; and Gendai, 91



- High-speed
- Large size and power hungry
- 2^N comparators
- Speed bottleneck usually large cap load at input
- Thermometer code out of comps
- Nands used for simpler decoding and/or bubble error correction
- Use comp offset cancellation



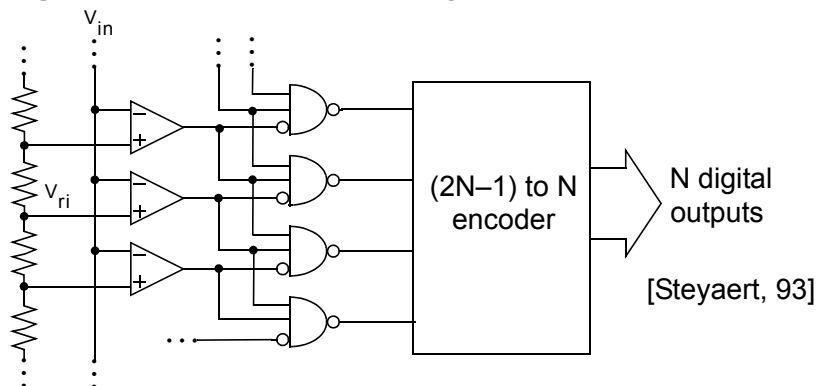
Issues in Designing Flash A/D Converters

- **Input Capacitive Loading** — use interpolating arch.
- **Resistor-String Bowing** — Due to I_{in} of bipolar comps — force center tap (or more) to be correct.
- **Signal and/or Clock Delay** — Small arrival diff in clock or input cause errors. (250MHz 8-bit A/D needs 5ps matching for 1LSB) — route clock and V_{in} together with the delays matched [Gendai, 1991]. Match capacitive loads
- **Substrate and Power-Supply Noise** — $V_{ref} = 2\text{ V}$ and 8-bit, 7.8 mV of noise causes 1 LSB error — shield clocks and use on-chip supply cap bypass
- **Flashback** — Glitch at input due to going from track to latch mode — use preamps in comparators and match input impedances



Flash Converters — Bubble Errors

- Thermometer code should be 1111110000
- Bubble error (noise, metastability)— 1111110100
- Usually occurs near transition point but can cause **gross errors** depending on encoder



- Can allow errors in lower 2 LSB but have MSBs encoder look at every 4th comp [Gendai, 91]



Reduced Auto-Zeroing

- Tsukamoto et al, ISSCC/96
- Spalding et al, ISSCC/96
- Reduce the auto-zero portion of conversion
 - auto zero when not performing conversion
 - add one more comparator and ripple up auto-zero

Advantages

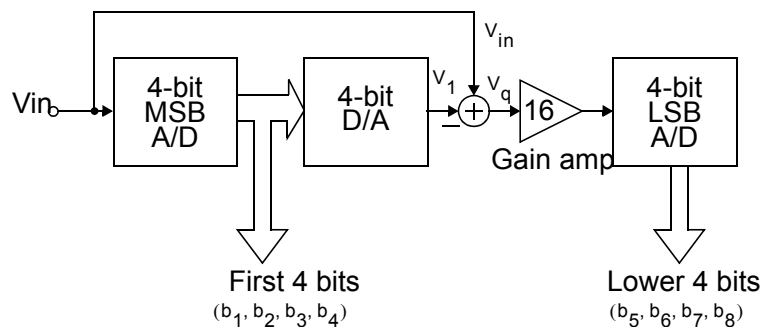
- **Lower power** — less current drawn from ref string
- **More speed** — more time for conversion

Disadvantage

- 1/f noise not rejected as much



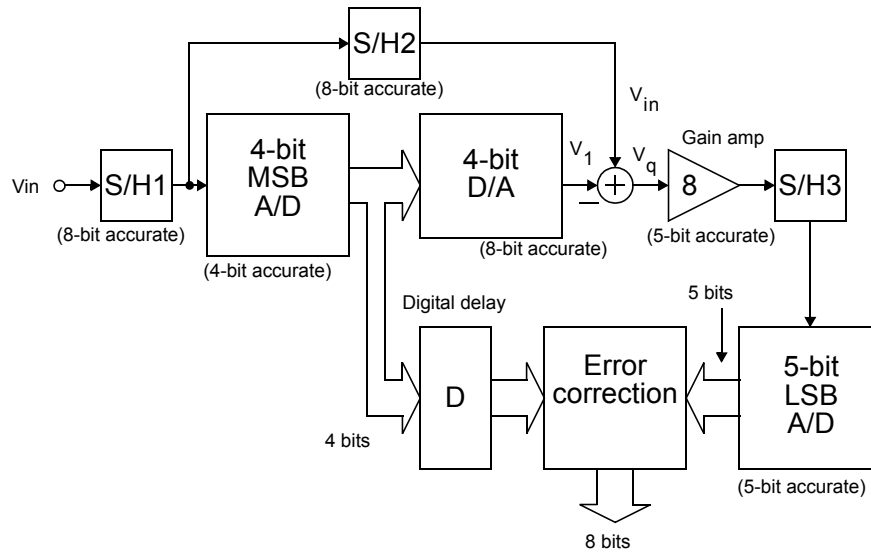
Two-Step A/D Converters



- High-speed, medium accuracy (but 1 sample latency)
- Less area and power than flash
- Only 32 comparators in above 8-bit two-step
- Gain amp likely sets speed limit
- Without digital error correction, many blocks need at least 8-bit accuracy



Digital Error Correction



- Relaxes requirements on input A/D
- Requires a 5-bit 2nd stage since V_q increased
- Example, see [Petschacher, 1990].

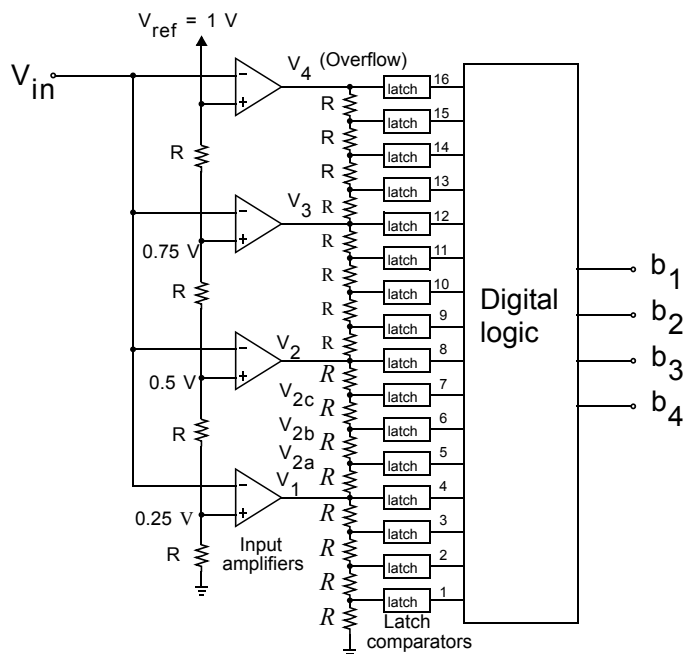


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Interpolating A/D Converters



- Goodenough, 1989
- Steyaert, 1993
- Kusumoto, 1993
- Use input amps to amplify input around reference voltages
- Latch thresholds less critical
- Less cap on input (faster than flash)
- Match delays to latches
- Often combined with folding architecture

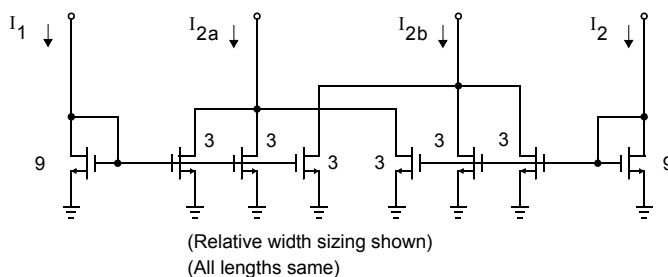
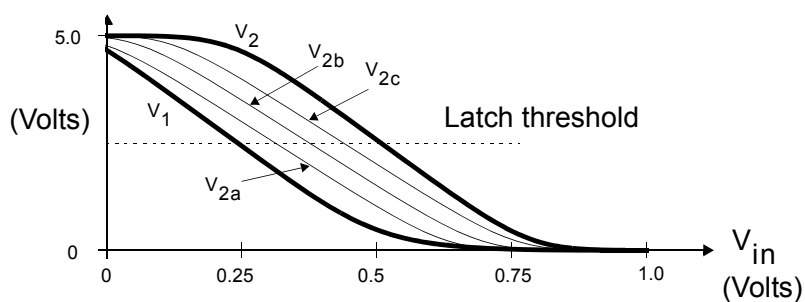


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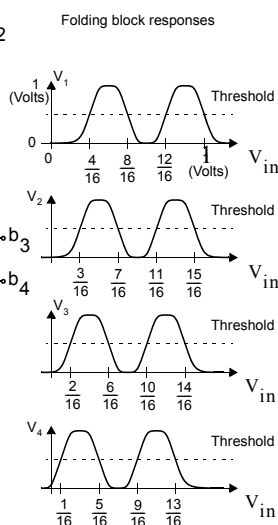
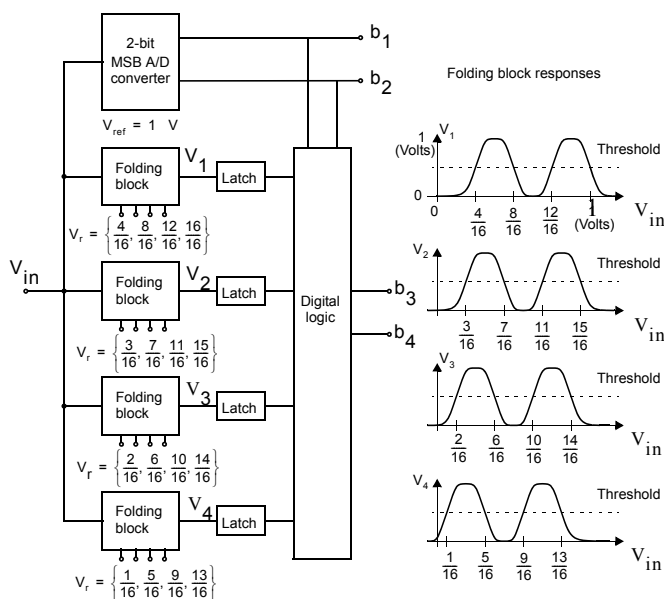
Interpolating Converters



current interpolation



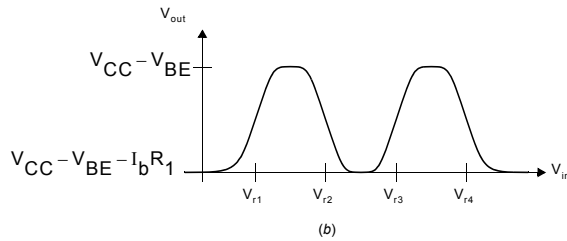
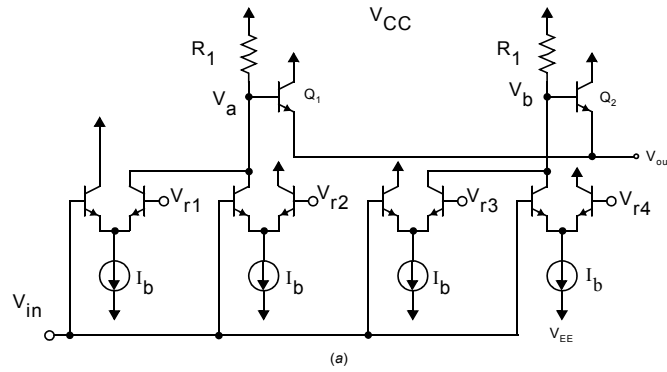
Folding A/D Converters



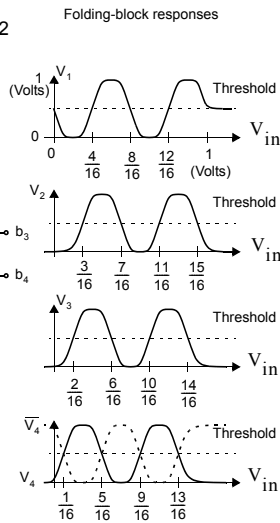
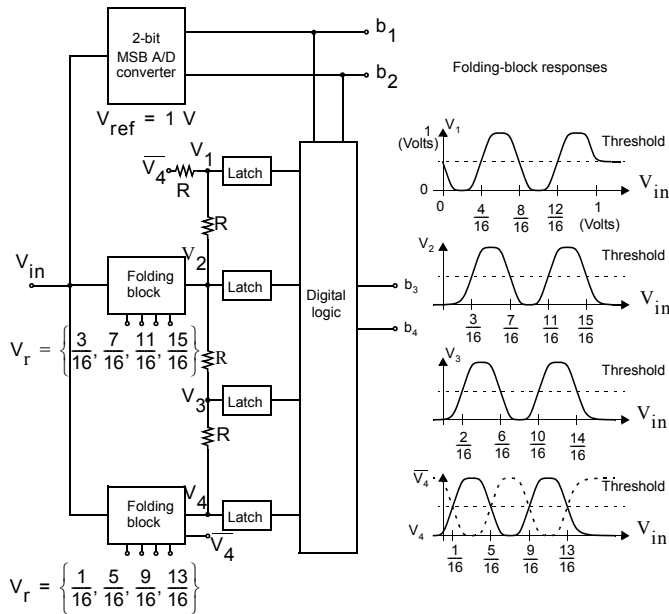
- Reduce number of latches using folding
- Save power and area
- Similar concept to 2-step
- Folding rate of 4 shown for 4 bit converter



Folding Circuit



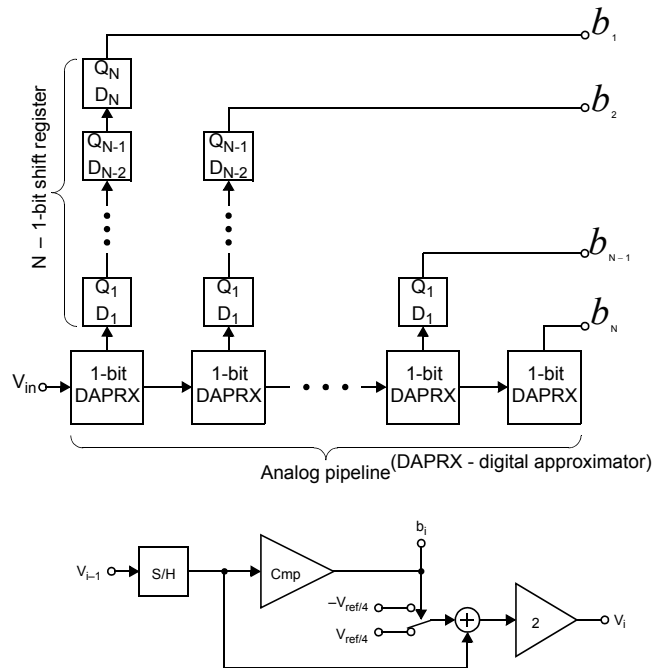
Folding with Interpolation



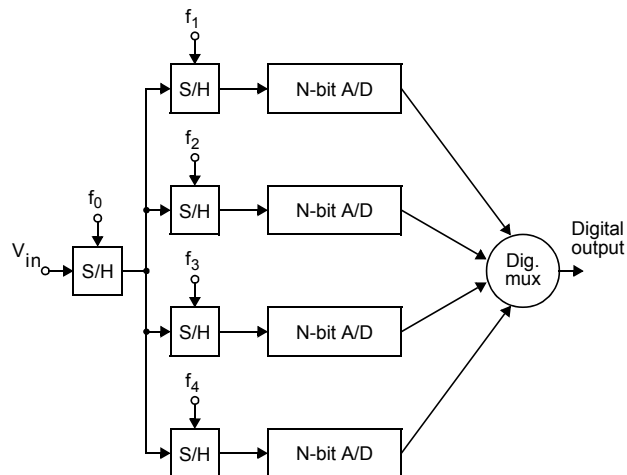
- Folding usually used with interpolation
- Reduces input cap (
- Without interp, same input cap as flash
- [van Valburg, 1992]
- [van de Grift, 1987]
- [Colleran, 1993]



Pipelined A/D Converters



Time-Interleaved A/D Converters [Black, 80]



- Use parallel A/Ds and multiplex them
- Tone occurs at f_s/N for N converters if mismatched
- Input S/H critical, others not — perhaps different tech for input S/H

